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Vishay Siliconix

# Automotive N-Channel 80 V (D-S) 175 °C MOSFET

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PRODUCT SUMMARY			
V <sub>DS</sub> (V)	80		
$R_{DS(on)}(\Omega)$ at $V_{GS} = 10 \text{ V}$	0.0030		
I <sub>D</sub> (A)	248		
Configuration	Single		
Package	PowerPAK SO-8L		

#### **FEATURES**

- TrenchFET® Gen IV power MOSFET
- AEC-Q101 qualified
- 100 % R<sub>q</sub> and UIS tested
- Q<sub>gd</sub>/Q<sub>gs</sub> ratio < 1 optimizes switching characteristics</li>
- Material categorization: for definitions of compliance please see www.vishav.com/doc?99912



O <sub>D</sub>
,
G T
N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)					
PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-source voltage		V <sub>DS</sub>	80	V	
Gate-source voltage		$V_{GS}$	± 20	V	
Continuous drain current	T <sub>C</sub> = 25 °C	-	248		
	T <sub>C</sub> = 125 °C	l <sub>D</sub>	143		
Continuous source current (diode conduction)		I <sub>S</sub>	248	Α	
Pulsed drain current		I <sub>DM</sub>	420		
Single pulse avalanche current	L = 0.1 mH	I <sub>AS</sub>	42		
Single pulse avalanche energy	L = 0.1 IIII	E <sub>AS</sub>	88	mJ	
Maximum power dissipation	T <sub>C</sub> = 25 °C	D	500	W	
	T <sub>C</sub> = 125 °C	P <sub>D</sub>	166	VV	
Operating junction and storage temperature range		T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C	
Soldering recommendations (peak temperature) <sup>b</sup>			260	C	

THERMAL RESISTANCE RATINGS					
PARAMETER		SYMBOL	LIMIT	UNIT	
Junction-to-ambient	PCB mount a	$R_{thJA}$	42	°C/W	
Junction-to-case (drain)		$R_{thJC}$	0.3	G/ VV	

#### Notes

- a. When mounted on 1" square PCB (FR4 material)
- b. See solder profile (<a href="www.vishay.com/doc?73257">www.vishay.com/doc?73257</a>). The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection



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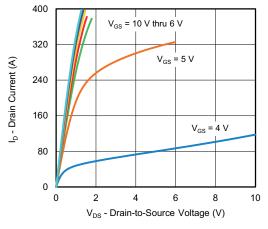
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-source breakdown voltage	V <sub>DS</sub>	$V_{GS} = 0$ , $I_D = 250 \mu A$		80	-	-	V
Gate-source threshold voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = 250 \mu A$		2.2	2.7	3.5	V
Gate-source leakage	I <sub>GSS</sub>	V <sub>DS</sub> =	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$		-	± 100	nA
		$V_{GS} = 0 V$	V <sub>DS</sub> = 80 V	-	-	10	
Zero gate voltage drain current	I <sub>DSS</sub>	$V_{GS} = 0 V$	V <sub>DS</sub> = 80 V, T <sub>J</sub> = 125 °C	-	-	50	μA
- <del>-</del>		$V_{GS} = 0 V$	V <sub>DS</sub> = 80 V, T <sub>J</sub> = 175 °C	-	-	250	
On-state drain current a	I <sub>D(on)</sub>	V <sub>GS</sub> = 10 V	V <sub>DS</sub> ≥ 5 V	30	-	-	Α
Drain-source on-state resistance <sup>a</sup>		V <sub>GS</sub> = 10 V	I <sub>D</sub> = 15 A	-	0.0025	0.0030	Ω
	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 15 A, T <sub>J</sub> = 125 °C	-	-	0.0059	
		V <sub>GS</sub> = 10 V	I <sub>D</sub> = 15 A, T <sub>J</sub> = 175 °C	-	-	0.0075	
Forward transconductance b	9 <sub>fs</sub>	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 10 A		-	82	-	S
Dynamic <sup>b</sup>				•		•	•
Input capacitance	C <sub>iss</sub>		V <sub>DS</sub> = 25 V, f = 1 MHz	-	4746	6645	pF
Output capacitance	C <sub>oss</sub>	$V_{GS} = 0 V$		-	814	1140	
Reverse transfer capacitance	C <sub>rss</sub>			-	51	72	
Total gate charge <sup>c</sup>	Qg		V <sub>DS</sub> = 40 V, I <sub>D</sub> = 10 A	-	78	117	nC
Gate-source charge <sup>c</sup>	Q <sub>gs</sub>	V <sub>GS</sub> = 10 V		-	18	-	
Gate-drain charge c	Q <sub>gd</sub>			-	16	-	
Gate resistance	Rg	f = 1 MHz		0.5	1.0	1.50	Ω
Turn-on delay time <sup>c</sup>	t <sub>d(on)</sub>				16	20	ns
Rise time <sup>c</sup>	t <sub>r</sub>	$V_{DD} = 40 \text{ V}, R_L = 4 \Omega$ $I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		-	10	15	
Turn-off delay time <sup>c</sup>	t <sub>d(off)</sub>			-	39	50	
Fall time <sup>c</sup>	t <sub>f</sub>			-	9	15	
Source-Drain Diode Ratings and Chara	cteristics <sup>b</sup>						
Pulsed current <sup>a</sup>	I <sub>SM</sub>				-	420	Α
Forward voltage	V <sub>SD</sub>	I <sub>F</sub> = 15 A, V <sub>GS</sub> = 0 V		-	-	1.1	V
Body diode reverse recovery time	t <sub>rr</sub>	I <sub>F</sub> = 10 A, di/dt = 100 A/μs		-	50	65	ns
Body diode reverse recovery charge	Q <sub>rr</sub>				71	95	nC
Reverse recovery fall time	t <sub>a</sub>			-	28	44	ns
Reverse recovery rise time	t <sub>b</sub>			-	22	38	
Body diode peak reverse recovery current	I <sub>RM(REC)</sub>			-	2.4	3.6	Α

#### Notes

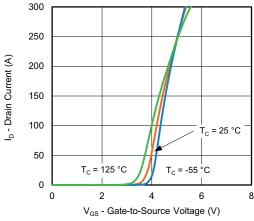
- a. Pulse test; pulse width  $\leq$  300 µs, duty cycle  $\leq$  2 %
- b. Guaranteed by design, not subject to production testing
- c. Independent of operating temperature

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

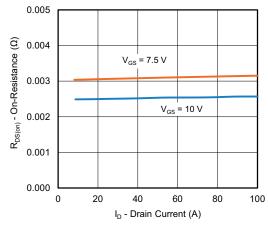




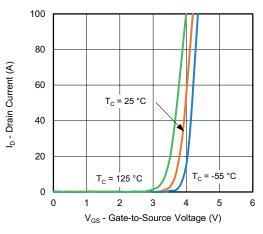
#### **Output Characteristics**



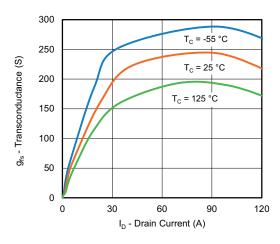
### Transfer Characteristics



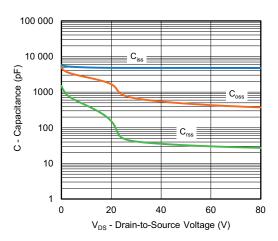
On-Resistance vs. Drain Current



#### **Transfer Characteristics**

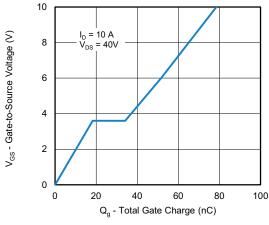


#### Transconductance

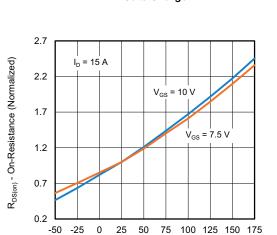


Capacitance

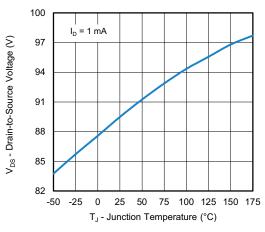




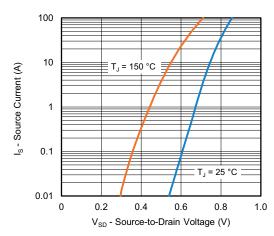




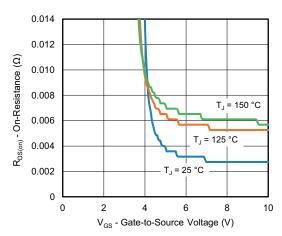
 $\label{eq:TJ-Junction} T_{J} \text{ - Junction Temperature (°C)}$  On-Resistance vs. Junction Temperature



**Drain Source Breakdown vs. Junction Temperature** 

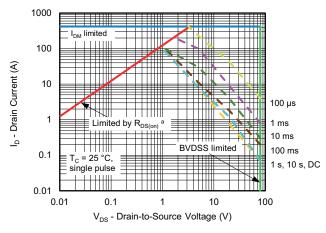


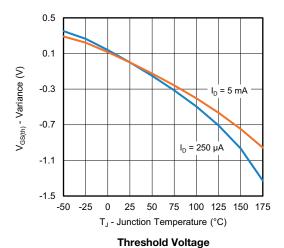
**Source Drain Diode Forward Voltage** 



On-Resistance vs. Gate-to Source Voltage





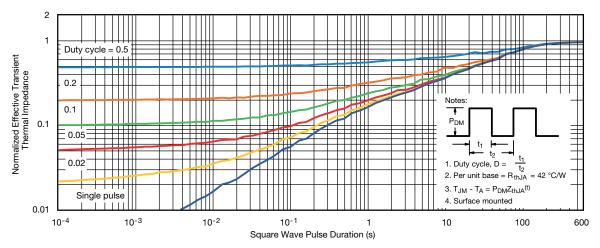


#### Safe Operating Area

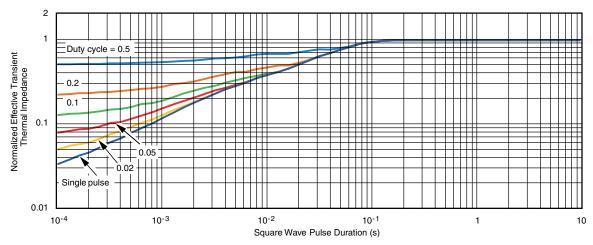
#### Note

a.  $V_{GS}$  > minimum  $V_{GS}$  at which  $R_{DS(on)}$  is specified





Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case

#### Note

- The characteristics shown in the two graphs
  - Normalized Transient Thermal Impedance Junction-to-Ambient (25 °C)
  - Normalized Transient Thermal Impedance Junction-to-Case (25 °C) are given for general guidelines only to enable the user to get a "ball park" indication of part capabilities. The data are extracted from single pulse transient thermal impedance characteristics which are developed from empirical measurements. The latter is valid for the part mounted on printed circuit board FR4, size 1" x 1" x 0.062", double sided with 2 oz. copper, 100 % on both sides. The part capabilities can widely vary depending on actual application parameters and operating conditions

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